



Attorney's Docket No. 046190.268023

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re: Viktorovitch et al.
Appl. No.: 10/635,713
Filed: August 5, 2003
For: OPTOELECTRONIC DEVICE WITH WAVELENGTH
FILTERING BY CAVITY COUPLING

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT
CITATION UNDER 37 C.F.R. § 1.97

Sir:

Attached is a list of documents on form PTO-1449. In accordance with the Office waiver published July 11, 2003, copies of the cited U.S. patents and patent application publications are not enclosed. Applicant does enclose copies of any cited foreign patent documents and non-patent literature in accordance with 37 CFR 1.98(a)(2).

It is requested that the Examiner consider these documents and officially make them of record in accordance with the provisions of 37 C.F.R. § 1.97 and Section 609 of the MPEP. By submitting the listed documents, Applicant in no way makes any admission as to the prior art status of the listed documents, but is instead submitting the listed documents for the sake of full disclosure.

Respectfully submitted,

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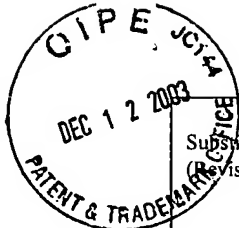
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Barbara Yates

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(Revised 04/2003)

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet 1 of 2

Complete if Known

Application Number	10/635,713
Filing Date	August 5, 2003
First Named Inventor	Viktorovitch et al.
Group Art Unit	
Examiner Name	
Attorney Docket Number	046190.268023

U. S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number Number - Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages of Relevant Figures Appear
	1	5,103,340	04-07-1992	Dono et al.	
	2	5,225,930	07-06-1993	Land et al.	

FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Foreign Patent Document Country Code - Number Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	English Language Translation Attached
	3	WO 98/17968	04-30-1998	Micron Optics, Inc.		
	4	EP 0903615 A2	03-24-1999	Nippon Telegraph and Telephone Corp.		

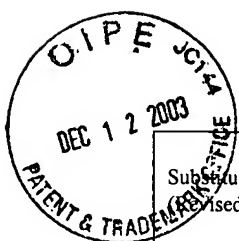
OTHER DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	English Language Translation Attached
	5	LAMPERSKI, JAN, "Discretely Tunable Multi Cavity FFP Filter for Standard WDM Frequency Grid," 2000 Electronic Components and Technology Conference, Las Vegas, Nevada, May 21-24, 2000, pgs. 1572-1575, XP-002178773, Piscataway, NJ, USA.	
	6	SALEH, A.A.M. and STONE, J., "Two-Stage Fabry-Perot Filters as Demultiplexers in Optical FDMA LAN's," Journal of Lightwave Technology, February 1989, pgs. 323-330, Vol. 7, No. 2, XP 000006106, New York, USA.	
	7	SPISSER, A., et al., "Highly Selective and Widely Tunable 1.55-MUM InP/Air-Gap Micromachined Fabry-Perot Filter for Optical Communications," IEEE Photonics Technology Letters, September 1998, pgs. 1259-1261, Vol. 10, No. 9, XP-000783228, New York, USA.	
	8	JAIN, ANIL, et al., "Dual Tunable Fabry-Perot Spectrally Agile Filter," Optical Engineering, March/April 1984, pgs. 159-166, Vol. 23, No. 2, XP-000997092, Minneapolis, MN.	
	9	GUNNING, WILLIAM, "Double-cavity electrooptic Fabry-Perot tunable filter," Applied Optics, September 1, 1982, pgs. 3129-3131, Vol. 21, No. 17, XP-000997094, Thousand Oaks, CA.	
	10	WU, M.S. etc., "Widely tunable 1.5 µm micromechanical optical filter using Al0x/AlGaAs DBR," Electronics Letters, September 25, 1997, pgs. 1702-1704, Vol. 33, No. 20, U.S.A.	
	11	Tayebati, P., etc., "Microelectromechanical tuneable filters with 0.47 nm linewidth and 70 nm tuning range," Electronics Letters, January 8, 1998, pgs. 76-77, Vol. 34, No. 1, U.S.A.	

Examiner
Signature

Date
Considered

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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Sheet 2 of 2

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OTHER DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	English Language Translation Attached
	12	Tayebati, P., etc., "Widely tunable Fabry-Perot Filter Using Ga(Al)As-A10 _x Deformable Mirrors," IEEE Photonics Technology Letters, March 1998, pgs. 394-396, Vol. 10, No. 3, U.S.A.	
	13	Tayebati, P., etc., "Microelectromechanical tunable filter with stable half symmetric cavity," Electronics Letters, October 1, 1998, pgs. 1967-1968, Vol. 34, No. 20, U.S.A.	
	14	Rondi, D., etc., "Highly selective 1.55 μ m InP/air gap micromachined Fabry-Perot filter for optical communications," Electronics Letters, March 5, 1998, pgs. 453-455, Vol. 34, No. 5, U.S.A.	
	15	International Search Report from corresponding International Application No. PCT/FR02/00402, dated January 24, 2003.	
Examiner Signature			Date Considered

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